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Napotek za uporabo statističnih metod na področju kakovosti in industrijske standardizacije

Guidance on the application of statistical methods to quality and to industrial standardization

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Lignes directrices pour l'application des méthodes statistiques à la qualité et à la normalisation industrielle

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Contents

Page

Foreword ix

Introduction x

1 Scope 1

2 Normative references 1

3 Terms and definitions 1

4 Illustration of value and role of statistical method through examples 1
4.1 Statistical method 1
4.2 Example 1: Strength of wire 2
4.2.1 General 2
4.2.2 Overall test results and lower specification limit 2
4.2.3 Initial analysis 3
4.2.4 Preliminary investigation 3
4.2.5 General discussion on findings 6
4.2.6 Explanation of statistical terms and tools used in this example 6
4.3 Example 2: Mass of fabric 7
4.3.1 General 7
4.3.2 Test results and specification limits 7
4.3.3 Discussion of specific results 10
4.3.4 Discussion on general findings 11
4.4 Example 3: Mass fraction of ash (in %) in a cargo of coal 11
4.4.1 General 11
4.4.2 Test results (reference ISO 11648-1: *Statistical aspects of sampling from bulk materials*) 12
4.4.3 Initial graphical analysis of specific results 12
4.4.4 Benefits of a statistically sound sampling plan 14
4.4.5 General conclusions 16

5 Introduction to basic statistical tools 16
5.1 General 16
5.2 Basic statistical terms and measures 16
5.3 Presentation of data 19
5.3.1 Dot or line plot 19
5.3.2 Tally chart 19
5.3.3 Stem and leaf plot 19
5.3.4 Box plot 20
5.3.5 Multi-vari chart 22
5.3.6 Position-Dimension (P-D) diagram 23
5.3.7 Graphical portrayal of frequency distributions 25
5.3.8 The normal distribution 31
5.3.9 The Weibull distribution 35
5.3.10 Graphs 41
5.3.11 Scatter diagram and regression 41
5.3.12 Pareto (or Lorenz) diagram 43
5.3.13 Cause and effect diagram 44

6 Variation and sampling considerations 45
6.1 Statistical control and process capability 45
6.1.1 Statistical control 45
6.1.2 Erratic variation 47
6.1.3 Systematic variation 47
6.1.4 Systematic changes with time 48
6.1.5 Statistical indeterminacy 49

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6.1.6 Non-normal variation 49
6.1.7 Quality level and process capability 49
6.2 Sampling considerations 50

7 Methods of conformity assessment 54
7.1 The statistical concept of a population 54
7.2 The basis of securing conformity to specification 55
7.2.1 The two principal methods 55
7.2.2 Considerations of importance to the customer 56
7.2.3 Considerations of importance to the supplier 56

8 The statistical relationship between sample and population 57
8.1 The variation of the mean and the standard deviation in samples 57
8.1.1 General 57
8.1.2 Variation of means 58
8.1.3 Variation of standard deviations 60
8.2 The reliability of a mean estimated from stratified and duplicate sampling 64
8.2.1 Stratified sampling 64
8.2.2 Duplicate sampling 66
8.3 Illustration of the use of the mean mass, and the lowest mass, in a sample of prescribed size of specimens of fabric 67
8.4 Tests and confidence intervals for means and standard deviations 69
8.4.1 Confidence intervals for means and standard deviations 69
8.4.2 Tests for means and standard deviations 71
8.4.3 Equivalence of methods of testing hypotheses 77
8.5 Simultaneous variation in the sample mean and in the sample standard deviation 77
8.6 Tests and confidence intervals for proportions 80
8.6.1 Attributes 80
8.6.2 Estimating a proportion 80
8.6.3 Confidence intervals for a proportion 81
8.6.4 Comparison of a proportion with a given value 82
8.6.5 Comparison of two proportions 82
8.6.6 Sample size determination 83
8.7 Prediction intervals 84
8.7.1 One-sided prediction interval for the next m observations 84
8.7.2 Two-sided prediction interval for the next m observations 85
8.7.3 One and two-sided prediction intervals for the mean of the next m observations 85
8.8 Statistical tolerance intervals 86
8.8.1 Statistical tolerance intervals for normal populations 86
8.8.2 Statistical tolerance intervals for populations of an unknown distributional type 87
8.8.3 Tables for statistical tolerance intervals 87
8.9 Estimation and confidence intervals for the Weibull distribution 87
8.9.1 The Weibull distribution 87
8.10 Distribution-free methods: estimation and confidence intervals for a median 88

9 Acceptance sampling 89
9.1 Methodology 89
9.2 Rationale 90
9.3 Some terminology of acceptance sampling 91
9.3.1 Acceptance quality limit (AQL) 91
9.3.2 Limiting quality (LQ) 91
9.3.3 Classical versus economic methods 92
9.3.4 Inspection levels 92
9.3.5 Inspection severity and switching rules 92
9.3.6 Use of “non-accepted” versus “rejected” 93
9.4 Acceptance sampling by attributes 93
9.4.1 General 93
9.4.2 Single sampling 94
9.4.3 Double sampling 96
9.4.4 Multiple sampling 96
9.4.5 Sequential sampling 99

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SIST-TP ISO/TR 18532:2010
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9.4.6 Continuous sampling 100
9.4.7 Skip-lot sampling 101
9.4.8 Audit sampling 102
9.4.9 Sampling for parts per million 102
9.4.10 Isolated lots 103
9.4.11 Accept-zero plans 103
9.5 Acceptance sampling by variables — Single quality characteristic 104
9.5.1 General 104
9.5.2 Single sampling plans by variables for known process standard deviation — The "σ" method 105
9.5.3 Single sampling plans by variables for unknown process standard deviation — The "s" method 106
9.5.4 Double sampling plans by variables 109
9.5.5 Sequential sampling plans by variables for known process standard deviation 110
9.5.6 Accept-zero plans by variables 110
9.6 Multiple quality characteristics 111
9.6.1 Classification of quality characteristics 111
9.6.2 Unifying theme 111
9.6.3 Inspection by attributes for nonconforming items 111
9.6.4 Inspection by attributes for nonconformities 112
9.6.5 Independent variables 113
9.6.6 Dependent variables 113
9.6.7 Attributes and variables 113

10 Statistical process control (SPC) 113
10.1 Process focus 113
10.2 Essence of SPC 116
10.3 Statistical process control or statistical product control? 117
10.4 Over-control, under-control and control of processes 118
10.4.1 General 118
10.4.2 Scenario 1: Operator reacts to each individual sample giving rise to process over-control 119
10.4.3 Scenario 2: Operator monitors a process using a run chart giving rise to haphazard control 120
10.4.4 Scenario 3: Monitoring using SPC chart with a potential for effective control 121
10.5 Key statistical steps in establishing a standard performance-based control chart 122
10.5.1 General 122
10.5.2 Monitoring strategy 122
10.5.3 Construction of a standard control chart 125
10.6 Interpretation of standard Shewhart-type control charts 127
10.7 Selection of an appropriate control chart for a particular use 128
10.7.1 Overview 128
10.7.2 Shewhart-type control charts 129
10.7.3 Cumulative sum (cusum) charts 129

11 Process capability 130
11.1 Overview 130
11.2 Process performance versus process capability 131
11.3 Process capability for measured (i.e. variables) data 132
11.3.1 General 132
11.3.2 Estimation of process capability (normally distributed data) 132
11.3.3 Estimation of process capability (non-normally distributed data) 133
11.4 Process capability indices 138
11.4.1 General 138
11.4.2 The C_p index 138
11.4.3 The C_{pk} family of indices 139
11.4.4 The C_{pm} index 142
11.5 Process capability for attribute data 145

12 Statistical experimentation and standards 148
12.1 Basic concepts 148
12.1.1 What is involved in experimentation? 148

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SIST-TP ISO/TR 18532:2010
https://standards.iteh.ai/catalog/standards/sist/446d075d-8149-4e10-9dc6-15ef021cb3eb/sist-tp-iso-tr-18532-2010

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12.1.2 Why experiment? ... 148
12.1.3 Where does statistics come in? ... 149
12.1.4 What types of standard experimental designs are there and how does one make a choice of which to use? ... 149

13 Measuring systems ... 164
13.1 Measurements and standards ... 164
13.2 Measurements, result quality and statistics ... 165
13.3 Examples of statistical methods to ensure quality of measured data ... 166
13.3.1 Example 1: Resolution ... 166
13.3.2 Example 2: Bias and precision ... 169
13.3.3 Precision — Repeatability ... 171
13.3.4 Precision — Reproducibility ... 172

Annex A (informative) Measured data control charts: Formulae and constants ... 177

Bibliography ... 181

Index ... 188

Figure 1 — Dot plot of breaking strength of 64 test specimens ... 2
Figure 2 — Basic cause and effect diagram for variation in wire strength (due to possible changes of material and process parameters within specified tolerances) ... 3
Figure 3 — Line plots showing patterns of results after division into rational groups ... 4
Figure 4 — Diagram indicating the effect of the interrelationship between oil quench temperature and steel temperature on wire strength ... 5
Figure 5 — Means of masses plotted against sample number (illustrating decreasing variation in the mean with the sample size increase) ... 9
Figure 6 — Ranges of masses within each sample vs sample number [illustrating increasing (range) variation within a sample with sample size increase] ... 9
Figure 7 — Averages of mass fraction of ash (in %) of coal by lot from cargo ... 13
Figure 8 — Progressive averages of mass fraction of ash (in %) in terms of lot ... 13
Figure 9 — Schematic diagram showing plan for sampling percentage ash from cargo of ship ... 14
Figure 10 — Mass fraction of ash (in %) plotted against test number for lots 19 and 20 (illustrating relative consistency of percentage ash within each of these lots) ... 15
Figure 11 — Mass fraction of ash (in %) plotted against test number for lots 9 and 10 (illustrating rogue pairs in both lots) ... 15
Figure 12 — Line plot of breaking strength of wire (Table 1 data) ... 19
Figure 13 — Typical tally charts ... 19
Figure 14 — Stem and leaf plot for data ... 20
Figure 15 — Box plot ... 21
Figure 16 — Box plot for Delta E panel shade variation between supply sources ... 21
Figure 17 — Multi-vari chart as a tool for process variation analysis ... 23
Figure 18 — Measurements on cylinder to determine nominal size, ovality and taper ... 23
Figure 19 — Measurement on cylinder — P-D diagrams showing ideal diameter values, pure taper and pure ovality ... 24
Figure 20 — Measurement on cylinder — P-D diagrams indicating progressive decrease of mean and increase in geometric form variation and the beneficial effects of overhaul ... 25
Figure 21 — Frequency histogram for immersion times in Table 6 ... 27
Figure 22 — Percentage frequency histogram for immersion times in Table 6 ... 27
Figure 23 — Cumulative percentage frequency histogram for immersion times in Table 6 ... 28
Figure 24 — Cumulative percentage frequency diagram for immersion times in Table 6 ... 29
Figure 25 — Normal curve overlaid on the immersion time histogram (mean = 6,79; standard deviation = 1,08) ... 30
Figure 26 — Straight line plot on normal probability paper indicating normality of data in Table 6 ... 31
Figure 27 — Percentages of normal distribution in relation to distances from the mean in terms of standard deviations ... 32
Figure 28 — Standard normal probability density with indications of percentage expected beyond a value, U or L, that is z standard deviation units from the mean ... 33
Figure 29 — Comparison with Weibull distributions, all with $\alpha = 1$ ... 37

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https://standards.iteh.ai/catalog/standards/sist/446d075d-8f90-4e16-9dc8-25eff21eb3eb/sist-tp-iso-tr-18532-2010

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Figure 30 — Q-Q plot to assess the fit of days between accidents (data in column one of Table 8) to a Weibull distribution 39
Figure 31 — Weibull probability plot of days between accidents (data in column one of Table 8) 40
Figure 32 — Scatter diagrams of four data sets that all have the same correlation coefficients (r) and fitted regression lines 43
Figure 33 — Relative contribution of different types of in-process paint faults 44
Figure 34 — Process cause and effect diagram for cracks in a casting 45
Figure 35 — Diagram indicating types of variation in samples 47
Figure 36 — Contrast of the capabilities of two filling machines 50
Figure 37 — Illustration of one-sided test 73
Figure 38 — Scatter chart for sample means and standard deviations in canned tomatoes data 78
Figure 39 — Standardized control chart for mean and standard deviation 79
Figure 40 — Type A and B OC curves for $n = 32$, Ac = 2, $N = 100$ 94
Figure 41 — Type B OC curves for Ac = 0, 1/3,1/2 and 1 95
Figure 42 — OC curves for single, double and multiple sampling size code letter L and AQL 2,5 % 97
Figure 43 — Average sample size (ASSI) curves for single, double and multiple sampling plans for sample size code letter L and AQL 2,5 % 98
Figure 44 — Curves for the double and multiple sampling plans for sample size code letter L and AQL 2,5 % showing the probability of needing to inspect significantly more sample items than under single sampling 99
Figure 45 — Example of sequential sampling by attributes for percent nonconforming 100
Figure 46 — Acceptance chart for a lower specification limit 106
Figure 47 — Acceptance charts for double specification limits with separate control 107
Figure 48 — Standardized acceptance chart for sample size 18 for double specification limits with combined control at an AQL of 4 % under normal inspection 107
Figure 49 — Standardized acceptance chart for sample size 18 for double specification limits with combined control at an AQL of 1 % for the upper limit and an AQL of 4 % overall under normal inspection 108
Figure 50 — ISO 9001:2008 Model of a process-based quality management system 114
Figure 51 — Control chart for nonconforming underwear 117
Figure 52 — Outline of process of applying a topcoat to a photographic film 118
Figure 53 — Probability of setter/operator observing a single mass value when mean = 45 119
Figure 54 — Example of process run chart with variation, but with no guidance on how to interpret and deal with variation 121
Figure 55 — Example of process control chart with criteria for “out-of-control” signals 122
Figure 56 — A two factor nested design is the basis of an $\bar{X}\,R$ chart (illustrated with a subgroup size of 3) 123
Figure 57 — Effect of subgroup size on ability to detect changes in process mean (process nominal = 5,00, process standard deviation = 0,01) 124
Figure 58 — Mean and range chart for masses of standard specimens of fabric 126
Figure 59 — Graphical comparison of process capability with specified tolerance 133
Figure 60 — Illustration of the estimation of capability with a skew distribution (equivalent to a range of $\pm 3\sigma$ in a normal distribution) 134
Figure 61 — Dot plot for percent of silicon data showing overall pattern of variation 135
Figure 62 — Probability plot for percent of silicon data showing overall pattern of variation 136
Figure 63 — Probability plot for the logarithm of percent of silicon data showing overall pattern of variation 137
Figure 64 — Individuals control chart of ln percent of silicon with limits 137
Figure 65 — Relationship between C_{p} and $C_{\mathrm{pk}U}$ and $C_{\mathrm{pk}L}$ for two sets of process variability and locations of specification limits 141
Figure 66 — Comparison of conformance to toleranced specification with optimal value approach 144
Figure 67 — Printed circuit board faults SPC chart and cumulative faults per unit (FPU) chart 147
Figure 68 — Effect of lubrication, speed, surface finish and density on push-off strength 154
Figure 69 — Interaction between squeegee speed and ink viscosity 155
Figure 70 — Central composite design of the face-centred cube variety for 3 factors 156
Figure 71 — Computer-generated contour plot for oxide uniformity in terms of power and pulse of the etching process for gas ratio fixed at its coded level 0 158
Figure 72 — Illustration of the fundamental difference in designs for two independent factors as compared with a two-component mixture 159

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Figure 73 — Illustration of the fundamental difference in designs for three independent factors as compared with a three-component mixture 160
Figure 74 — Ten-point augmented simplex centroid three-component design 160
Figure 75 — Response surface contours for mean burn rate in terms of fuel (X1), oxidize (X2) and binder (X3) blend components 161
Figure 76 — Response surface contours for standard deviation of burn rate in terms of fuel (X1), oxidize (X2) and binder (X3) blend components 161
Figure 77 — Factors A and B set at nominal to give a process yield of 68 % 162
Figure 78 — First stage optimisation using Box EVOP 163
Figure 79 — First stage Box EVOP as local optimum has been found 163
Figure 80 — Incomplete 5 stage simplex maximization experiment for two factors in terms of yield . 164
Figure 81 — Recommended resolution for process control and determination of compliance with specified tolerance 167
Figure 82 — Range charts showing adequate and inadequate resolutions 168
Figure 83 — Bias and precision 169
Figure 84 — Effect of measuring systems uncertainty on compliance decision 170
Figure 85 — Establishing bias and precision for a pressure gauge 171
Figure 86 — Individuals and moving range chart for pressure to check for stability of results prior to performing a bias and precision test 172

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Introduction

This Technical Report demonstrates the advantages in the application of statistical methods in as simple and efficient a manner as possible so that they become accessible to the many rather than to the few.

As an introduction to the subject, three examples are given in Clause 4 to focus attention on some of the wider questions at issue. These examples suggest how statistical thinking coupled with the use of simple statistical tools and technical and operational knowledge of the process can help in improving designs, process efficiency and performance and product conformity to specification.

— Example 1, relating to the strength of wire, illustrates the role and value of division of data into so-called rational subgroups coupled with the use of cause and effect diagrams and line plots. It also shows how to exploit interrelationships between process parameters to achieve robust designs. The need is emphasized to treat numerical data not just as a set of figures but as potentially meaningful information on a process. It demonstrates clearly that an enquiring mind and sound judgement, coupled with an understanding of the actual process producing the numerical data, are required as distinct from a mere knowledge of statistical method. This indicates the need for non-statisticians to become more aware of the role of statistical method and to become more involved in their actual application to secure the maximum possible benefits to any organization.

— Example 2, on fabric mass, illustrates key aspects that need to be considered when sampling to establish conformance of an entity to specification. In this example, general conclusions are established by statistical theory and are turned to practical use.

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— Example 3 concerns the mass fraction of ash (in %) in coal. Specifically, it demonstrates four principal concepts: how to handle apparent fluctuation of quality within a quantity of material; the need to determine, on a sound basis, the amount of sampling necessary to estimate the quality of a commodity; the necessity to establish, in advance, a well designed sampling procedure; and the value of progressive analysis of results, in a simple graphical manner, as they become available.

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More generally, example 3 illustrates the importance of the application of statistical thinking and design method to a numerical study prior to it being undertaken. It also indicates that, to gain full benefit from such a study, persons familiar with the activity under scrutiny should be involved throughout.

Clause 5 introduces basic statistical terms and measures, and a wide range of simpler statistical tools used to present and analyse data. Emphasis has been placed on a pictorial approach that can most readily be communicated to, and understood by, the many.

Clause 6 describes the fundamentals of sampling on a statistical basis and distinguishes between statistical uniformity (stability of a process) and quality level (process capability). Clause 7 introduces sampling with reference to a product requirement. It draws out the two principal methods, *viz*. that of after the event acceptance sampling and that of the ongoing control of inherently capable processes. Clause 8 provides a detailed treatment of the statistical relationship between sample and batch. Clause 9 describes the methodology, terminology and rationale of acceptance sampling. Single, double, multiple, sequential, continuous, skip-lot, audit, parts per million, isolated lot and accept-zero plans for acceptance sampling by attributes are dealt with. Acceptance sampling by variables covers the following plans for individual quality characteristics: single sampling plans for known and for unknown standard deviation; double sampling plans; sequential sampling plans for known standard deviation and accept-zero plans. Multiple-quality characteristic plans are also described.

Clause 10 covers the fundamentals of statistical process control. It distinguishes between statistical process control and the use of statistical process control techniques for statistical product control. Over-control, under-control and control are discussed. The key steps in establishing and interpreting performance-based control charts that are intended primarily to differentiate between special and common causes of variation and

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provide a basis for capability and performance assessment are covered. The principal types of Shewhart-type control charts and the role and application of cumulative sum (CUSUM) charts are dealt with.

Clause 11 deals with performance benchmarking of stable processes under the heading of process capability assessment. Three very pertinent business questions are answered by a control chart: 1) is the process in control?; 2) what is the performance of the process?; and 3) is there evidence of significant improvement in process performance? Clause 11 focuses on answering the second question regarding process capability/performance of both measured data and attribute processes. It introduces the use of the internationally standardized capability indices, C_{p}, $C_{\mathrm{pk}L}$ and $C_{\mathrm{pk}U}$. It also discusses the business implications, in terms of aiming at preferred value and minimizing variation, with the quotation of minimum C_{pm} values, rather than the convention of tolerating maximum use of specified tolerances in determining whether or not an entity conforms to requirements.

Clause 12 begins by illustrating the role and value of simple economic experimental designs where the mathematical content is such that all the necessary calculations can readily be done manually. It then continues to exploit the development of computer software programs in the design and analysis of experiments. Nowadays the need for computational skills has become so minimal that the practitioner can concentrate his attention on choosing the right kind of design for a particular application, how to perform the experiment and how to interpret the computer outputs. In both cases, pictorial outputs are encouraged to facilitate understanding.

Clause 13 deals with the capability of measuring systems. Following a resumé of the basic statistical requisites of a measuring system that ensures the integrity of the data output, examples are given of the application of statistical method to the evaluation of resolution, bias and precision, uncertainty, repeatability and reproducibility.

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Guidance on the application of statistical methods to quality and to industrial standardization

1 Scope

This Technical Report describes a broad range of statistical methods applicable to the management, control and improvement of processes.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 3534-1, *Statistics — Vocabulary and symbols — Part 1: General statistical terms and terms used in probability*

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ISO 3534-2, *Statistics — Vocabulary and symbols — Part 2: Applied statistics*

ISO 3534-3, *Statistics — Vocabulary and symbols — Part 3: Design of experiments*

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3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 3534-1, ISO 3534-2 and ISO 3534-3 apply.

4 Illustration of value and role of statistical method through examples

4.1 Statistical method

The term “statistics” is commonly associated with an idea of lists of numbers, whether relating to output, costs, sales, prices or wages. It is thus advisable to make clear at the outset what in fact this statistical method is that may gainfully be applied in the field of quality and standardization. It is important to give some preliminary answers to certain questions. Why is statistical method needed at all? What does it consist of?

What kind of assistance can it give? Where can, when can, and should, it be applied? For this purpose, it has seemed best to deal first with the particular rather than the general, using specific examples to focus attention on the wider issues involved.

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